

# SIC MOSFET CoolSiC™ MOSFET 650 V G2

Built on Infineon's robust 2<sup>nd</sup> generation Silicon Carbide trench technology, the 650 V CoolSiC™ MOSFET delivers unparalleled performance, superior reliability, and great ease of use. It enables cost effective, highly efficient, and simplified designs to fulfill the ever-growing system and market needs.

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#### **Features**

- Ultra-low switching losses
- Benchmark gate threshold voltage,  $V_{GS(th)} = 4.5 \text{ V}$
- Robust against parasitic turn-on even with 0 V turn-off gate voltage
- Flexible driving voltage and compatible with bipolar driving scheme
- Robust body diode operation under hard commutation events
- .XT interconnection technology for best-in-class thermal performance

#### **Benefits**

- · Enables high efficiency and high power density designs
- Facilitates great ease of use and integration
- Provides the best price performance ratio compared to Industry's most ambitious roadmaps
- · Reduces the size, weight and bill of materials of the systems
- Enhances system robustness and reliability

### Potential applications

- SMPS
- Solar PV inverters
- · Energy storage and battery formation
- UPS
- EV charging infrastructure
- Motor drives

#### **Product validation**

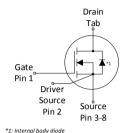
Fully qualified according to JEDEC for Industrial Applications

Please note: The source and driver source pins are not exchangeable. Their exchange might lead to malfunction.



Parameter	Value	Unit
$V_{\rm DSS}$ over full $T_{\rm j,range}$	650	V
$R_{\mathrm{DS(on),typ}}$	14.5	mΩ
R <sub>DS(on),max</sub>	18	mΩ
$Q_{G,typ}$	79	nC
I <sub>D,pulse</sub>	400	А
Q <sub>oss</sub> @ 400 V	148	nC
E <sub>oss</sub> @ 400 V	20.1	μЈ

Part number	Package	Marking	Related links
IMT65R015M2H	PG-HSOF-8	65R015M2	see Appendix A







#### Public

# CoolSiC™ MOSFET 650 V G2 IMT65R015M2H



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# 1 Maximum ratings

at  $T_i = 25$ °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Parameter	Symphol		Values		Linit	Note / Test condition
Parameter	Symbol	Min.	Тур.	Max.	Onic	
Continuous DC drain current 1)	I <sub>DDC</sub>	-	-	131 95	А	$T_c = 25$ °C $T_c = 100$ °C
Peak drain current <sup>2)</sup>	I <sub>DM</sub>	-	-	400	Α	$T_{\rm c}$ = 25°C, $V_{\rm GS}$ = 18 V
Avalanche energy, single pulse	E <sub>AS</sub>	-	-	372	mJ	/ = 12.0 A // = 50 // soo table 11
Avalanche energy, repetitive	$E_{AR}$	-	-	1.86	mJ	<i>I</i> <sub>D</sub> = 13.9 A, <i>V</i> <sub>DD</sub> = 50 V; see table 11
Avalanche current, single pulse	I <sub>AS</sub>	-	-	13.9	А	-
MOSFET <i>dv/dt</i> ruggedness	dv/dt	-	-	200	V/ns	V <sub>DS</sub> = 0400 V
Gate source voltage (static) 3)	$V_{GS}$	-7	-	23	V	-
Gate source voltage (transient)	$V_{\rm GS}$	-10	-	25	V	t <sub>p</sub> ≤ 500 ns, duty cycle ≤ 1%
Power dissipation	P <sub>tot</sub>	-	-	535	W	T <sub>c</sub> = 25°C
Storage temperature	$T_{\rm stg}$	-55	-	150	°C	
Operating junction temperature	T <sub>j</sub>	-55	-	175	°C	-
Mounting torque	-	-	-	n.a.	Ncm	
Continuous reverse drain current <sup>1)</sup>	I <sub>SDC</sub>	-	-	131 92	А	$V_{GS} = 18 \text{ V}, T_c = 25^{\circ}\text{C}$ $V_{GS} = 0 \text{ V}, T_c = 25^{\circ}\text{C}$
Peak reverse drain current <sup>2)</sup>	I <sub>SM</sub>	-	-	400 121	А	$T_{\rm c} = 25$ °C, $t_{\rm p} \le 250$ ns $T_{\rm c} = 25$ °C
Insulation withstand voltage	V <sub>ISO</sub>	-	-	n.a.	V	$V_{\rm rms}$ , $T_{\rm c} = 25$ °C, $t = 1$ min

<sup>1)</sup> Limited by  $T_{\rm j,max}$ .

<sup>&</sup>lt;sup>2)</sup> Pulse width  $t_{\rm pulse}$  limited by  $T_{\rm j,max}$ .

<sup>3)</sup> The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



# 2 Thermal characteristics

#### Table 3 Thermal characteristics

Davamakan	Comple		Values		11	Note / Test condition
Parameter	Symbol	Min.	Тур.	Max.		
Thermal resistance, junction - case	$R_{th(j-c)}$	-	-	0.28	°C/W	Not subject to production test. Parameter verified by design/characterization according to JESD51-14.
Soldering temperature, reflow soldering allowed	$T_{\rm sold}$	-	-	260	°C	reflow MSL3



# 3 Operating range

#### Table 4 Operating range

Parameter	Symbol		Values		Unit	Note / Test condition
Parameter	Syllibot	Min.	Тур.	Max.		Note / Test condition
Recommended turn-on voltage	$V_{\rm GS(on)}$	-	18	-	٧	
Recommended turn-off voltage	$V_{\rm GS(off)}$	-	0	-	V	<del>-</del>



#### 4 Electrical characteristics

at  $T_i = 25$ °C, unless otherwise specified

Table 5 Static characteristics

Davanatas	Symbol		Values			Nicke / Took can distant
Parameter	Symbol	Min.	Тур.	Max.	Onic	Note / Test condition
Drain-source voltage	$V_{\rm DSS}$	650	-	-	V	$V_{\rm GS} = 0 \text{ V}, I_{\rm D} = 1.3 \text{ mA}$
Gate threshold voltage <sup>4)</sup>	$V_{\rm GS(th)}$	3.5	4.5	5.6	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 13 \text{ mA}$
Zero gate voltage drain current	I <sub>DSS</sub>	-	1 3	75 -	μΑ	$V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 25^{\circ}\text{C}$ $V_{\rm DS} = 650 \text{ V}, V_{\rm GS} = 0 \text{ V}, T_{\rm j} = 175^{\circ}\text{C}$
Gate-source leakage current	I <sub>GSS</sub>	-	-	100	nA	$V_{\rm GS} = 20 \text{ V}, V_{\rm DS} = 0 \text{ V}$
Drain-source on-state resistance	$R_{ m DS(on)}$	-	19 14.5 13.2 24	- 18 - -	mΩ	$V_{GS} = 15 \text{ V}, I_D = 64.2 \text{ A}, T_j = 25^{\circ}\text{C}$ $V_{GS} = 18 \text{ V}, I_D = 64.2 \text{ A}, T_j = 25^{\circ}\text{C}$ $V_{GS} = 20 \text{ V}, I_D = 64.2 \text{ A}, T_j = 25^{\circ}\text{C}$ $V_{GS} = 18 \text{ V}, I_D = 64.2 \text{ A}, T_j = 175^{\circ}\text{C}$
Internal gate resistance	$R_{G,int}$	-	2.1	-	Ω	<i>f</i> =1 MHz

Tested after 1 ms pulse at  $V_{GS}$  = +20 V. "Linear mode" operation is not recommended. For assessment of potential "linear mode" operation, please contact Infineon sales office.

#### Table 6 Dynamic characteristics

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized. For layout recommendations please use provided application notes or contact Infineon sales office.

Parameter	Symbol		Values			Note / Test condition
rarameter	Symbol	Min.	Тур.	Max.	Onit	Note / Test condition
Input capacitance	$C_{\rm iss}$	-	2792	-	pF	
Reverse transfer capacitance	C <sub>rss</sub>	-	16	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$
Output capacitance 5)	C <sub>oss</sub>	-	207	269	pF	
Output charge <sup>5)</sup>	Q <sub>oss</sub>	-	148	192	nC	calculation based on C <sub>oss</sub>
Effective output capacitance, energy related <sup>6)</sup>	$C_{ m o(er)}$	-	251	-	pF	$V_{GS} = 0 \text{ V},$ $V_{DS} = 0400 \text{ V}$
Effective output capacitance, time related <sup>7)</sup>	$C_{ m o(tr)}$	-	371	-	pF	$I_{\rm D}$ = constant, $V_{\rm GS}$ = 0 V, $V_{\rm DS}$ = 0 400 V
Turn-on delay time	$t_{\sf d(on)}$	-	11.6	-	ns	
Rise time	t <sub>r</sub>	-	14.7	-	ns	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V},$ $I_{\rm D} = 64.2 \text{ A}, R_{\rm G,ext} = 1.8 \Omega;$ see table 10
Turn-off delay time	$t_{\sf d(off)}$	-	22	-	ns	
Fall time	$t_{f}$	-	6.4	-	ns	



#### Table 6 Dynamic characteristics

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized. For layout recommendations please use provided application notes or contact Infineon sales office.

Parameter	Symbol	Values			Linit	Note / Test condition
	Symbol	Min.	Тур.	Max.		Note / Test condition
Turn-ON switching losses <sup>8)</sup>	E <sub>on</sub>	-	84	-	μJ	
Turn-OFF switching losses <sup>8)</sup>	$E_{\rm off}$	-	138	-	μJ	$V_{\rm DD} = 400 \text{ V}, V_{\rm GS} = 0/18 \text{ V},$ $I_{\rm D} = 64.2 \text{ A}, R_{\rm G,ext} = 1.8 \Omega$
Total switching losses <sup>8)</sup>	E <sub>tot</sub>	-	222	-	μJ	1.0 0

<sup>5)</sup> Maximum specification is defined by calculated six sigma upper confidence bound.

Table 7 Gate charge characteristics

Parameter	Symbol		Values		Linit	Note / Test condition
	Syllibot	Min.	Тур.	Max.	Onit	Note / Test Condition
Plateau gate to source charge	$Q_{GS(pl)}$	-	20	-	nC	
Gate to drain charge	$Q_{GD}$	-	15	-		$V_{DD} = 400 \text{ V}, I_{D} = 64.2 \text{ A},$ $V_{GS} = 0 \text{ to } 18 \text{ V}$
Total gate charge	$Q_{G}$	-	79	-	nC	VGS 0 to 10 v

#### Table 8 Reverse diode characteristics

Parameter	Symbol		Values			Note / Test condition
raiailletei	Syllibol	Min.	Тур.	Max.	Oilit	Note / Test condition
Drain-source reverse voltage	$V_{\rm SD}$	-	4.3	-	V	$V_{GS} = 0 \text{ V}, I_{S} = 64.2 \text{ A}, T_{j} = 25^{\circ}\text{C}$
MOSFET forward recovery time	t <sub>fr</sub>	-	22 16	-	ns	$V_{DD} = 400 \text{ V}, I_{S} = 64.2 \text{ A},$ $di_{S}/dt = 1000 \text{ A/}\mu\text{s}; \text{ see table 9}$ $V_{DD} = 400 \text{ V}, I_{S} = 64.2 \text{ A},$ $di_{S}/dt = 4000 \text{ A/}\mu\text{s}; \text{ see table 9}$
MOSFET forward recovery charge <sup>9)</sup>	$Q_{\mathrm{fr}}$	-	154 258	-	nC	$V_{DD} = 400 \text{ V}, I_{S} = 64.2 \text{ A},$ $di_{S}/dt = 1000 \text{ A/}\mu\text{s}; \text{ see table 9}$ $V_{DD} = 400 \text{ V}, I_{S} = 64.2 \text{ A},$ $di_{S}/dt = 4000 \text{ A/}\mu\text{s}; \text{ see table 9}$
MOSFET peak forward recovery current	I <sub>frm</sub>	-	14.3 32	-	А	$V_{DD} = 400 \text{ V}, I_{S} = 64.2 \text{ A},$ $di_{S}/dt = 1000 \text{ A/}\mu\text{s}; \text{ see table 9}$ $V_{DD} = 400 \text{ V}, I_{S} = 64.2 \text{ A},$ $di_{S}/dt = 4000 \text{ A/}\mu\text{s}; \text{ see table 9}$

<sup>9)</sup>  $Q_{fr}$  includes  $Q_{oss}$ .

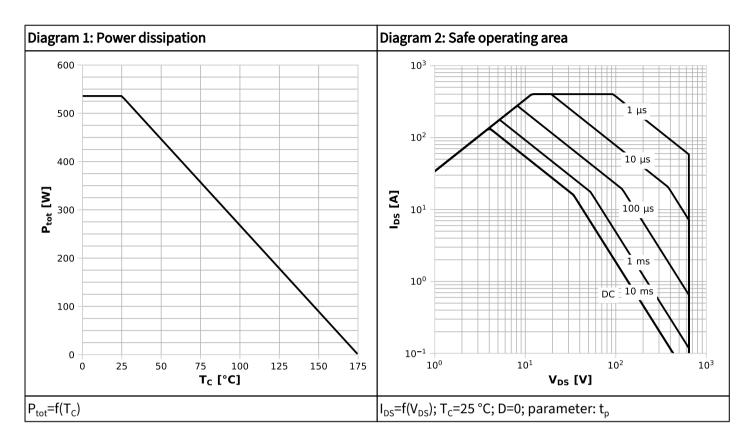
 $C_{o(er)}$  is a fixed capacitance that gives the same stored energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400 V.

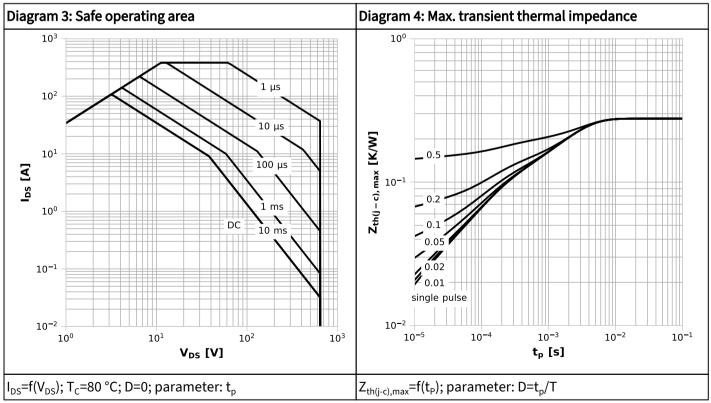
<sup>7)</sup>  $C_{o(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 400 V.

<sup>&</sup>lt;sup>8)</sup> Values for 4-pin configuration based on TO-263-7 measurements; MOSFET used in half-bridge configuration without external diode.

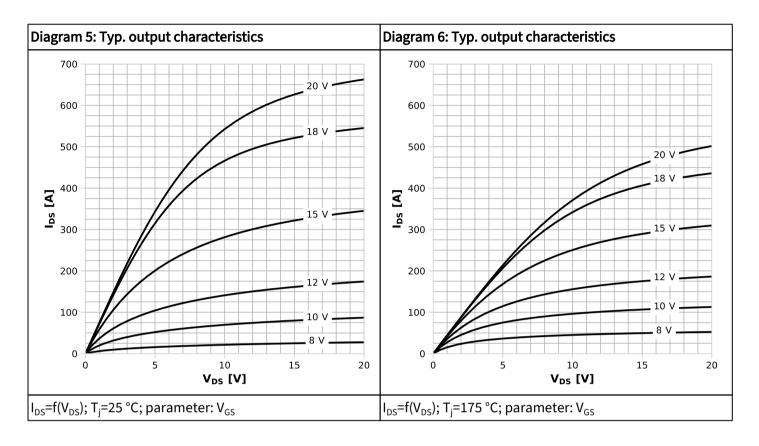


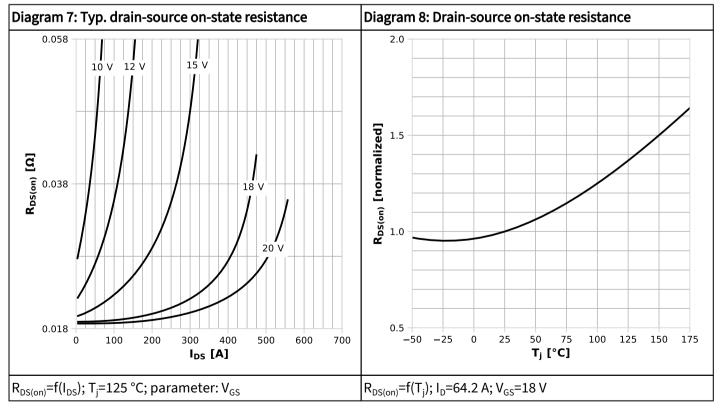
# 5 Electrical characteristics diagrams



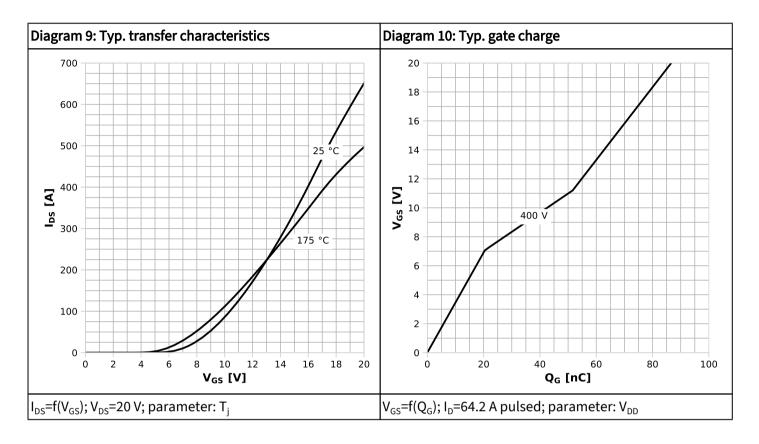


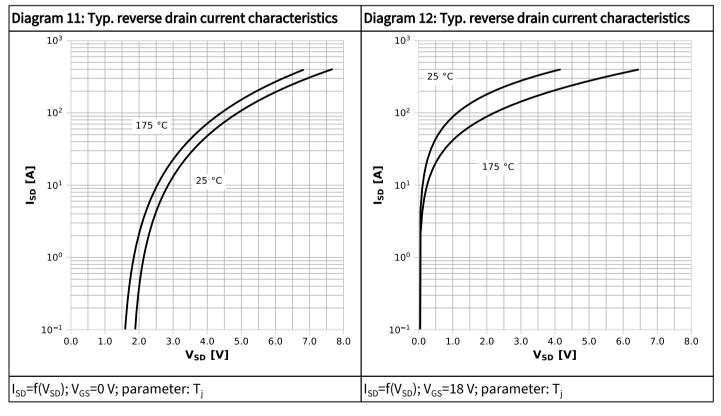




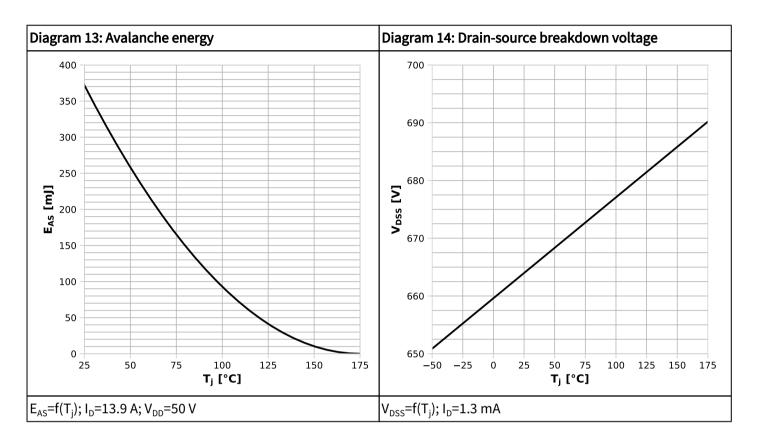


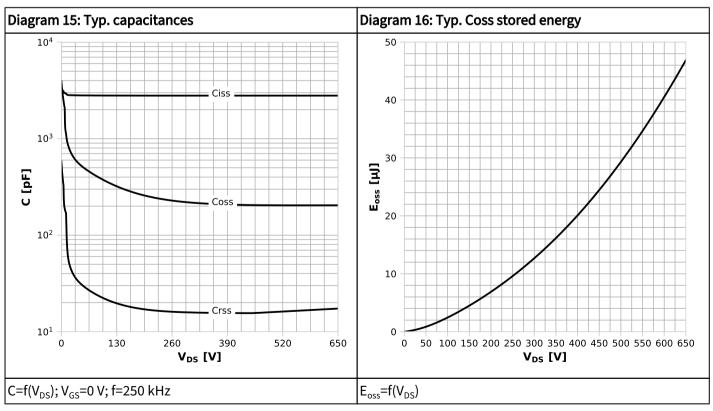




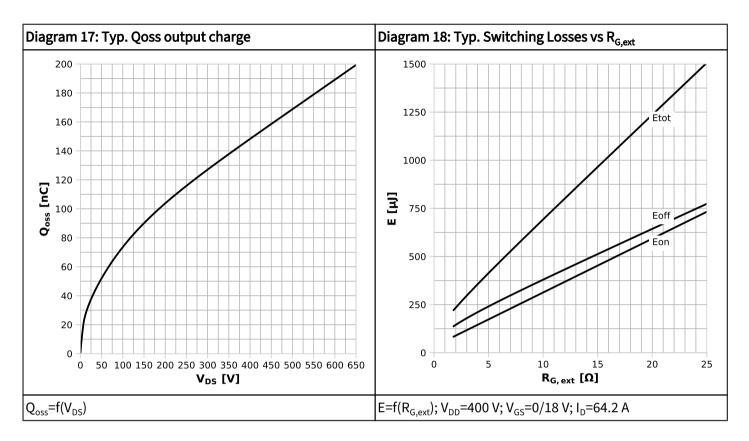


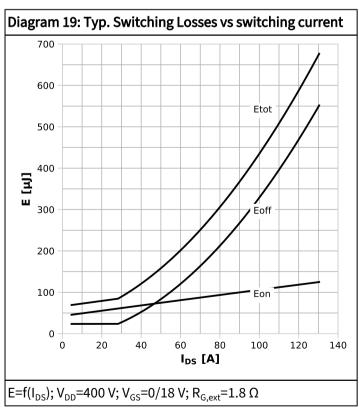














#### 6 Test circuits

Table 9 Body diode characteristics

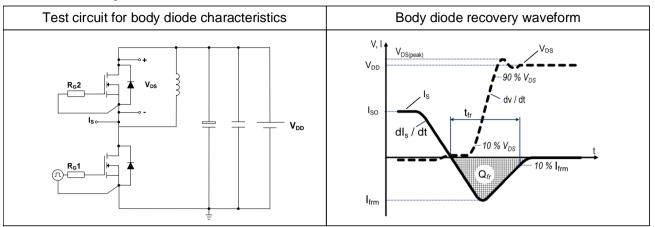


Table 10 Switching times

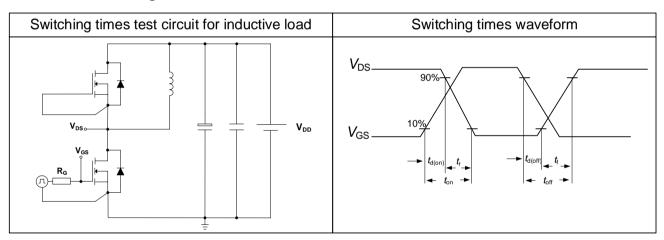
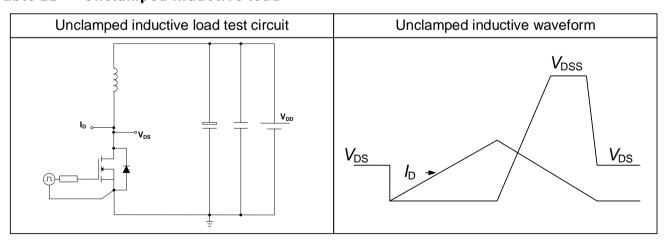
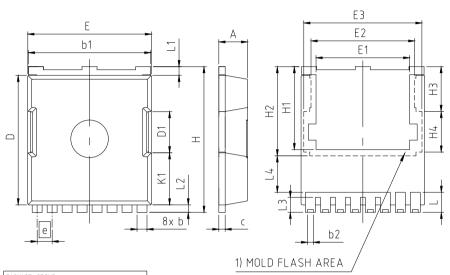


Table 11 Unclamped inductive load





# 7 Package outlines



PACKAGE - GROUP NUMBER:	PG-HSOF-8-U02						
DIMENSIONS	MILLIM	IETERS					
DIMENSIONS	MIN.	MAX.					
Α	2.20	2.40					
b	0.70	0.90					
b1	9.70	9.90					
b2	0.42	0.50					
С	0.40	0.60					
D	10.28	10.58					
D1	3.	30					
E	9.70	10.10					
E1	7.50						
E2	8.50						
E3	9.46						
е	1.20 (BSC)						
Н	11.48	11.88					
H1	6.55	6.95					
H2	7.15						
Н3	3.	59					
H4	3.26						
N	8						
K1	4.18						
L	1.40 1.80						
L1	0.50 0.90						
L2	0.50 0.70						
L3	1.00	1.30					
L4	2.62	2.81					

1) PARTIALLY COVERED WITH MOLD FLASH

Figure 1 Outline PG-HSOF-8, dimensions in mm



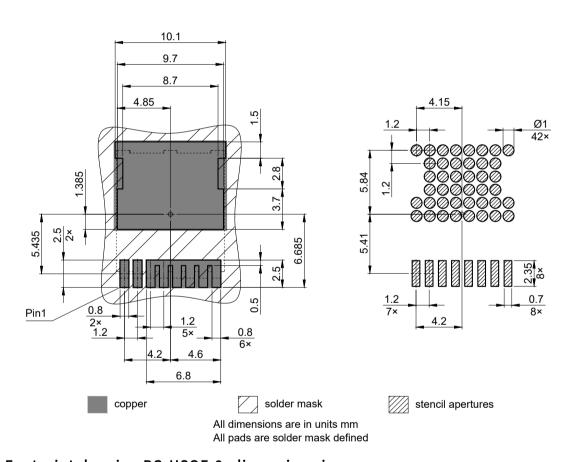


Figure 2 Footprint drawing PG-HSOF-8, dimensions in mm



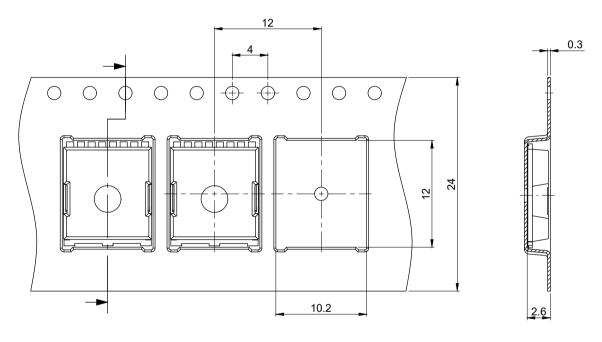


Figure 3 Packaging variant PG-HSOF-8, dimensions in mm



# 8 Appendix A

#### Table 12 Related links

- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Webpage
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Application Note
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Simulation Model
- IFX Design tools

# CoolSiC™ MOSFET 650 V G2



#### **Revision history**

IMT65R015M2H

#### Revision 2025-01-16, Rev. 2.1

#### Previous revisions

Revision	Date	Subjects (major changes since last revision)
2.0	2024-11-06	Release of final
2.1	2025-01-16	updated continuous reverse drain current

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